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Form PTO-1449			U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY, DOCKET NO. MI22-2461			SERIAL NO. 10/734,9			
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ATTY. DOCKET NO. Form PTO-1449 U.S. DEPARTMENT OF COMMERCE SERIAL NO. PRIORITY 10/229,887 PATENT AND TRADEMARK OFFICE MI22-2461 LIST OF ART CITED BY APPLICANT APPLICANT: Eugene Marsh et al. (Use several sheets if necessary) FILING DATE **GROUP** PRIORITY August 27, 2002 PRIORITY 2822 **U.S. PATENT DOCUMENTS** Class Subclass **Document** Date Name Filing Date Initials Number If Appropriate 6,482,262 B1 11/2002 Elers et al. 117 84 03/2003 6,534,395 B2 Werkhoven et al. 438 627 6,585,823 B1 07/2003 Van Wijck 117 89 AD 6,586,343 B1 07/2003 Ho et al. 438 758 Æ 20010024387 09/2001 Raaijmakers et al. 365 200 AF 20010041250 11/2001 Werkhoven et al. 428 212 AG 20010050039 A1 12/2001 Park 117 102 AH 20010054381 A1 12/2001 Umotoy et al. 715 118 6,613,587 81 09/2003 Carpenter et al. 345 473 FOREIGN PATENT DOCUMENTS Document Date Country Class Translation Yes No AJ AK AL. OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) AN AO DATE CONSIDERED *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE ATTY. DOCKET NO. SERIAL NO. PRIORITY 10/229,887 PATENT AND TRADEMARK OFFICE MI22-2461 LIST OF ART CITED BY APPLICANT APPLICANT: Eugene Marsh et al. (Use several sheets if necessary) **FILING DATE GROUP** PRIORITY August 27, 2002 PRIORITY 2822 **U.S. PATENT DOCUMENTS** Subclass Filing Date If Appropriate Initials Number 04/24/02 10/132,003 Dando et al. (as filed) AB Dando et al. (as filed) 04/24/02 10/132,767 10/150,388 Mardian et al. (as filed) 05/17/02 AD 6,620,253 B1 09/2003 Dando et al. 369 124.07 Æ 10/163,689 Derderian et al. (as filed) 06/05/02 AF 10/208,314 Castrovillo et al. (as filed) 07/29/02 AG 10/222,282 Sarigiannis et al. (as filed and amended) 08/15/02 AH 10/222,304 Sarigiannis et al. (as filed) 08/15/02 A FOREIGN PATENT DOCUMENTS Document Date Country Class Translation Subclas9 Number Yes No AJ. AK OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) AO DATE CONSIDERED *EXAMINER: Injural if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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